

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10556233	BIEHL ET AL.
	Examiner	Art Unit
	Cho, Jennifer Y	1621

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

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East Search	4/8/08	JC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner